

Description (Continued)

The AT27C512R is available in a choice of industry standard JEDEC-approved one-time programmable (OTP) plastic PDIP, PLCC, SOIC, an<u>d TSOP</u> packages. All devices feature two-line control (CE, OE) to give designers the flexibility to prevent bus contention.

With 64K byte storage capability, the AT27C512R allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's 27C512R has additional features to ensure high quality and efficient production use. The RapidTM Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100 μ s/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1 μ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

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AT27C512R

Block Diagram

V _{cc} - GND -			
OE/VPP - CE -	→	OE, CE AND PROGRAM LOGIC	OUTPUT BUFFERS
A0 A15	⁻⇒[Y DECODER	Y-GATING
A0 A15 ADDRESS	;	X DECODER	CELL MATRIX
INPUTS		A DECODER	IDENTIFICATION

Absolute Maximum Ratings*

Temperature Under Bias55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V ⁽¹⁾
Voltage on A9 with Respect to Ground2.0V to +14.0V ⁽¹⁾
V_{PP} Supply Voltage with Respect to Ground2.0V to +14.0V $^{(1)}$

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V_{CC} + 0.75V dc which may overshoot to +7.0V for pulses of less than 20 ns.

Operating Modes

Mode \ Pin	CE	OE/Vpp	Ai	Outputs
Read	VIL	VIL	Ai	Dout
Output Disable	VIL	VIH	X ⁽¹⁾	High Z
Standby	VIH	X ⁽¹⁾	Х	High Z
Rapid Program (2)	VIL	Vpp	Ai	D _{IN}
PGM Inhibit	Vih	Vpp	X ⁽¹⁾	High Z
Product Identification ⁽⁴⁾	VIL	VIL	$\begin{array}{l} A9 = V_{H} \stackrel{(3)}{}\\ A0 = V_{IH} \text{ or } V_{IL} \\ A1 - A15 = V_{IL} \end{array}$	Identification Code

Notes: 1. X can be V_{IL} or V_{IH} .

2. Refer to Programming Characteristics.

3. $V_{H} = 12.0 \pm 0.5 V$.

4. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.





DC and AC Operating Conditions for Read Operation

			AT27C512R								
		-45	-55	-70	-90	-12	-15				
Operating	Com.	0°C - 70°C									
Temp.(Case)	Ind.	-40°C - 85°C									
V _{CC} Supply		$5V\pm10\%$	$5V\pm10\%$	5V ± 10%	5V ± 10%	5V ± 10%	5V ± 10%				

DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to V_{CC}		±1	μΑ
ILO	Output Leakage Current	$V_{OUT} = 0V$ to V_{CC}		±5	μA
ISB	V _{CC} ⁽¹⁾ Standby Current	I _{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μA
128		I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V		1	mA
Icc	V _{CC} Active Current	$\frac{f = 5 \text{ MHz, } I_{OUT} = 0 \text{ mA,}}{CE} = V_{IL}$		20	mA
VIL	Input Low Voltage		-0.6	0.8	V
Vih	Input High Voltage		2.0	Vcc + 0.5	V
Vol	Output Low Voltage	I _{OL} = 2.1 mA		0.4	V
Vон	Output High Voltage	I _{OH} = -400 μA	2.4		V

Note: 1. V_{CC} must be applied simultaneously or before \overline{OE}/V_{PP} , and removed simultaneously or after \overline{OE}/V_{PP} .

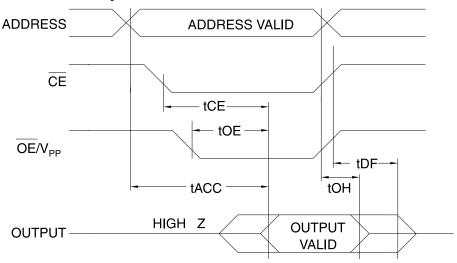
AC Characteristics for Read Operation

				AT			AT270	AT27C512R							
			-	45		55	-7	70	-9	90	-'	12	-1	5	
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Units
tacc ⁽³⁾	Address to Output Delay	$\overline{CE} = \overline{OE}/V_{PP}$ $= V_{IL}$		45		55		70		90		120		150	ns
t _{CE} ⁽²⁾	CE to Output Delay	$\overline{OE}/V_{PP} = V_{IL}$		45		55		70		90		120		150	ns
toe ^(2, 3)	OE/V _{PP} to Output Delay	$\overline{CE} = V_{IL}$		20		25		30		35		35		40	ns
tdf ^(4, 5)	OE/V _{PP} or CE High Output Float, whiche	to ever occurred first		20		20		25		25		30		35	ns
tон	Output Hold from Address, CE or OE/ whichever occurred		7		7		7		0		0		0		ns

Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

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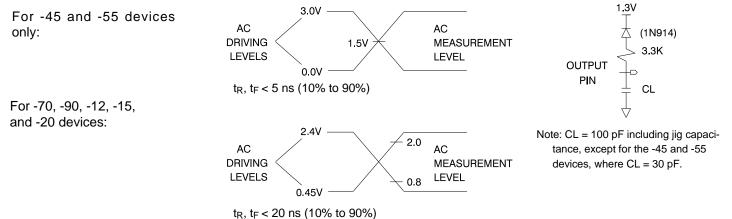
AC Waveforms for Read Operation ⁽¹⁾



- Notes: 1. Timing measurement reference level is 1.5V for -45 and -55 devices. Input AC drive levels are $V_{IL} = 0.0V$ and $V_{IH} = 3.0V$. Timing measurement reference levels for all other speed grades are $V_{OL} = 0.8V$ and $V_{OH} = 2.0V$. Input AC drive levels are $V_{IL} = 0.45V$ and $V_{IH} = \frac{2.4}{V}$.
- OE/V_{PP} may be delayed up to t_{ACC} t_{OE} after the address is valid without impact on t_{ACC}.
 This parameter is only sampled and is not 100% tested.
- Output float is defined as the point when data is no longer driven.
- 2. $\overline{\text{OE}}/\text{V}_{PP}$ may be delayed up to t_{CE} t_{OE} after the falling edge of $\overline{\text{CE}}$ without impact on t_{CE} .

Input Test Waveforms and Measurement Levels

Output Test Load



Pin Capacitance $(f = 1 \text{ MHz } T = 25^{\circ}\text{C})^{(1)}$

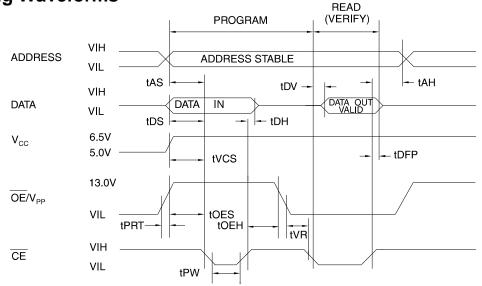
	Тур	Max	Units	Conditions	
CIN	4	6	pF	$V_{IN} = 0V$	
Соит	8	12	pF	$V_{OUT} = 0V$	

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.





Programming Waveforms



- Notes: 1. The Input Timing Reference is 0.8V for V_{IL} and 2.0V for V_{IH}
 - 2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.

DC Programming Characteristics

 T_{A} = 25 $\pm~$ 5°C, V_{CC} = 6.5 $\pm~$ 0.25V, $\overline{\text{OE}}/V_{\text{PP}}$ = 13.0 $\pm~$ 0.25V

		Test	Li	Limits			
Symbol	Parameter	Conditions	Min	Max	Units		
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA		
VIL	Input Low Level		-0.6	0.8	V		
Vih	Input High Level		2.0	V _{CC} + 1	V		
Vol	Output Low Voltage	$I_{OL} = 2.1 \text{ mA}$		0.4	V		
Vон	Output High Voltage	I _{OH} = -400 µA	2.4		V		
ICC2	V _{CC} Supply Current (Program and Verify)			25	mA		
I _{PP2}	OE/V _{PP} Current	$\overline{CE} = V_{IL}$		25	mA		
VID	A9 Product Identification Voltage		11.5	12.5	V		

AC Programming Characteristics

 T_{A} = 25 $\pm~$ 5°C, V_{CC} = 6.5 $\pm~$ 0.25V, $\overline{\text{OE}}/V_{\text{PP}}$ = 13.0 $\pm~$ 0.25V

Sym-	Test	Li	mits	Units
bol	Parameter Condtions* (1)	Min	Max	
tAS	Address Setup Time	2		μS
toes	OE/V _{PP} Setup Time	2		μS
toeh	OE/V _{PP} Hold Time	2		μS
t _{DS}	Data Setup Time	2		μS
tан	Address Hold Time	0		μS
tDH	Data Hold Time	2		μS
tDFP	CE High to Output Float Delay ⁽²⁾	0	130	ns
tvcs	V _{CC} Setup Time	2		μS
tpw	CE Program Pulse Width (3)	95	105	μS
tDV	Data Valid from $\overline{CE}^{(2)}$		1	μS
t∨R	OE/VPP Recovery Time	2		μS
tPRT	OE/VPP Pulse Rise Time During Programming	50		ns

*AC Conditions of Test:

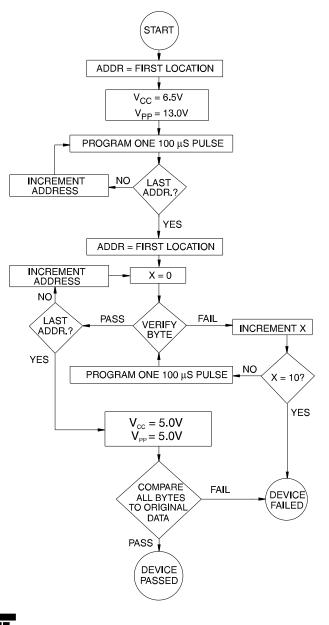
- Notes: 1. $\frac{V_{CC}}{OE}$ must be applied simultaneously or before $\frac{OE}{OE}$ /V_{PP} and removed simultaneously or after $\frac{OE}{OE}$ /V_{PP}.
 - This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
 - 3. Program Pulse width tolerance is 100 $\mu sec \pm 5\%.$

Atmel's 27C512R Integrated Product Identification Code

		Pins							Hex	
Codes	A0	07	O6	O5	O4	O3	O2	01	O 0	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	1	1	0	1	0D

Rapid Programming Algorithm

A 100 μ s \overline{CE} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and \overline{OE}/V_{PP} is raised to 13.0V. Each address is first programmed with one 100 μ s \overline{CE} pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, μ to 10 successive 100 μ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. \overline{OE}/V_{PP} is then lowered to V_{IL} and V_{CC} to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.





Ordering Information

tACC	lcc	(mA)		D .	
(ns)	Active	Standby	Ordering Code	Package	Operation Range
45	20	AT27C512R-45PC AT27C512R-45RC AT27C512R-45TC		32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-45JI AT27C512R-45PI AT27C512R-45RI AT27C512R-45TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
55	20	0.1	AT27C512R-55JC AT27C512R-55PC AT27C512R-55RC AT27C512R-55TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-55JI AT27C512R-55PI AT27C512R-55RI AT27C512R-55TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
70	20	0.1	AT27C512R-70JC AT27C512R-70PC AT27C512R-70RC AT27C512R-70TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-70JI AT27C512R-70PI AT27C512R-70RI AT27C512R-70TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
90	20	0.1	AT27C512R-90JC AT27C512R-90PC AT27C512R-90RC AT27C512R-90TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-90JI AT27C512R-90PI AT27C512R-90RI AT27C512R-90TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
120	20	0.1	AT27C512R-12JC AT27C512R-12PC AT27C512R-12RC AT27C512R-12RC AT27C512R-12TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)
	20	0.1	AT27C512R-12JI AT27C512R-12PI AT27C512R-12RI AT27C512R-12TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)
150	20	0.1	AT27C512R-15JC AT27C512R-15PC AT27C512R-15RC AT27C512R-15TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)

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Ordering Information (Continued)

tACC	lcc	(mA)	Ordering Code	Deekege	Operation Bongo		
(ns)	Active	Standby	Ordering Code	Package	Operation Range		
150	20	0.1	AT27C512R-15JI AT27C512R-15PI AT27C512R-15RI AT27C512R-15TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)		

Package Type	
32J	32 Lead, Plastic J-Leaded Chip Carrier (PLCC)
28P6	28 Lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)
28R	28 Lead, 0.330" Wide, Plastic Gull Wing Small Outline (SOIC)
28T	28 Lead, Thin Small Outline Package (TSOP)

